

正

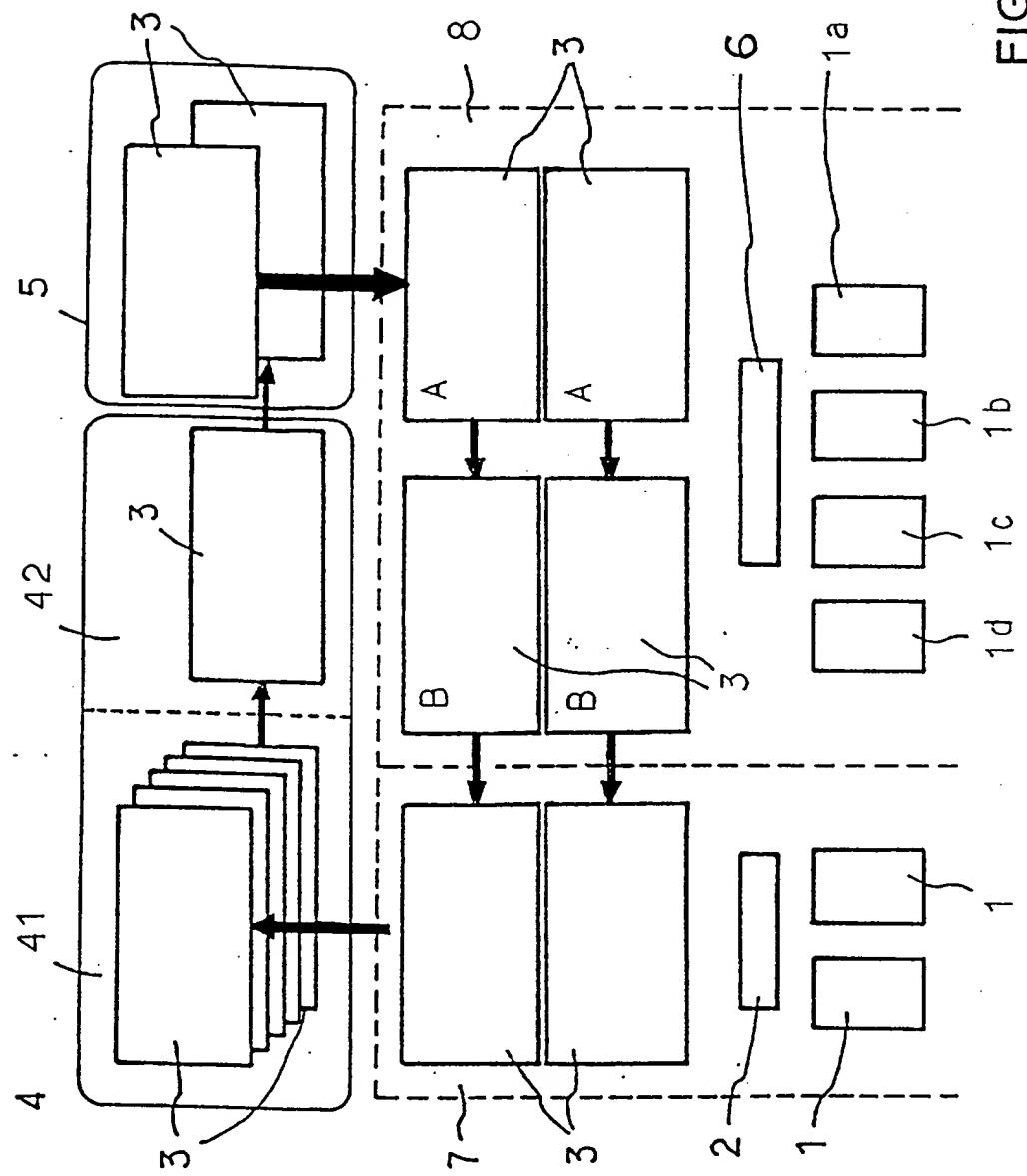


FIG. 2

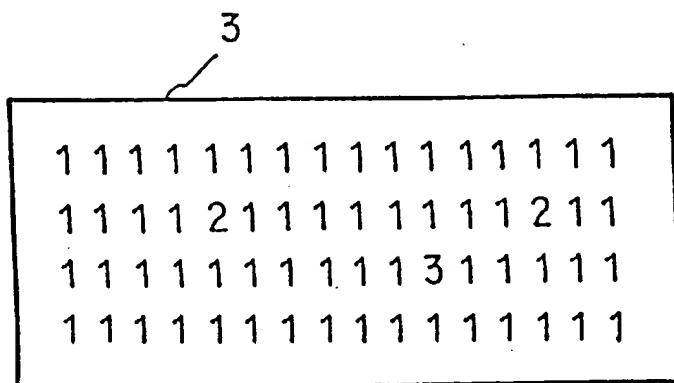


FIG. 3(a)

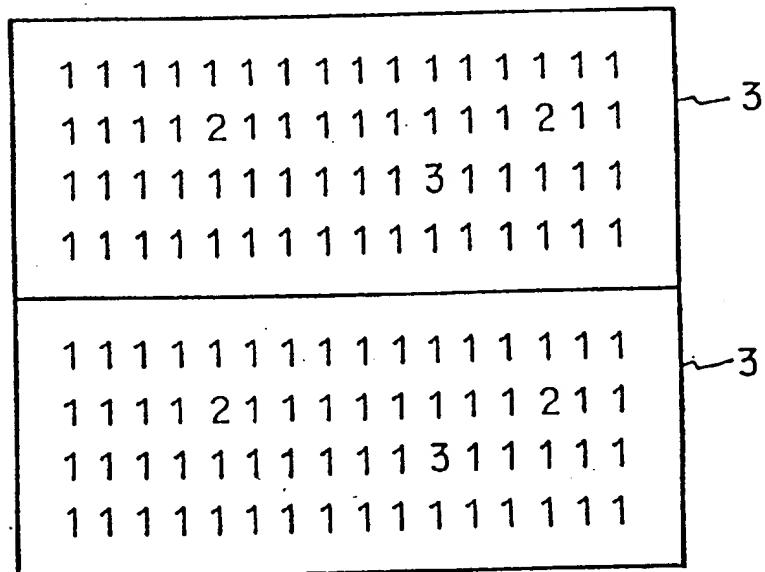


FIG. 3(b)

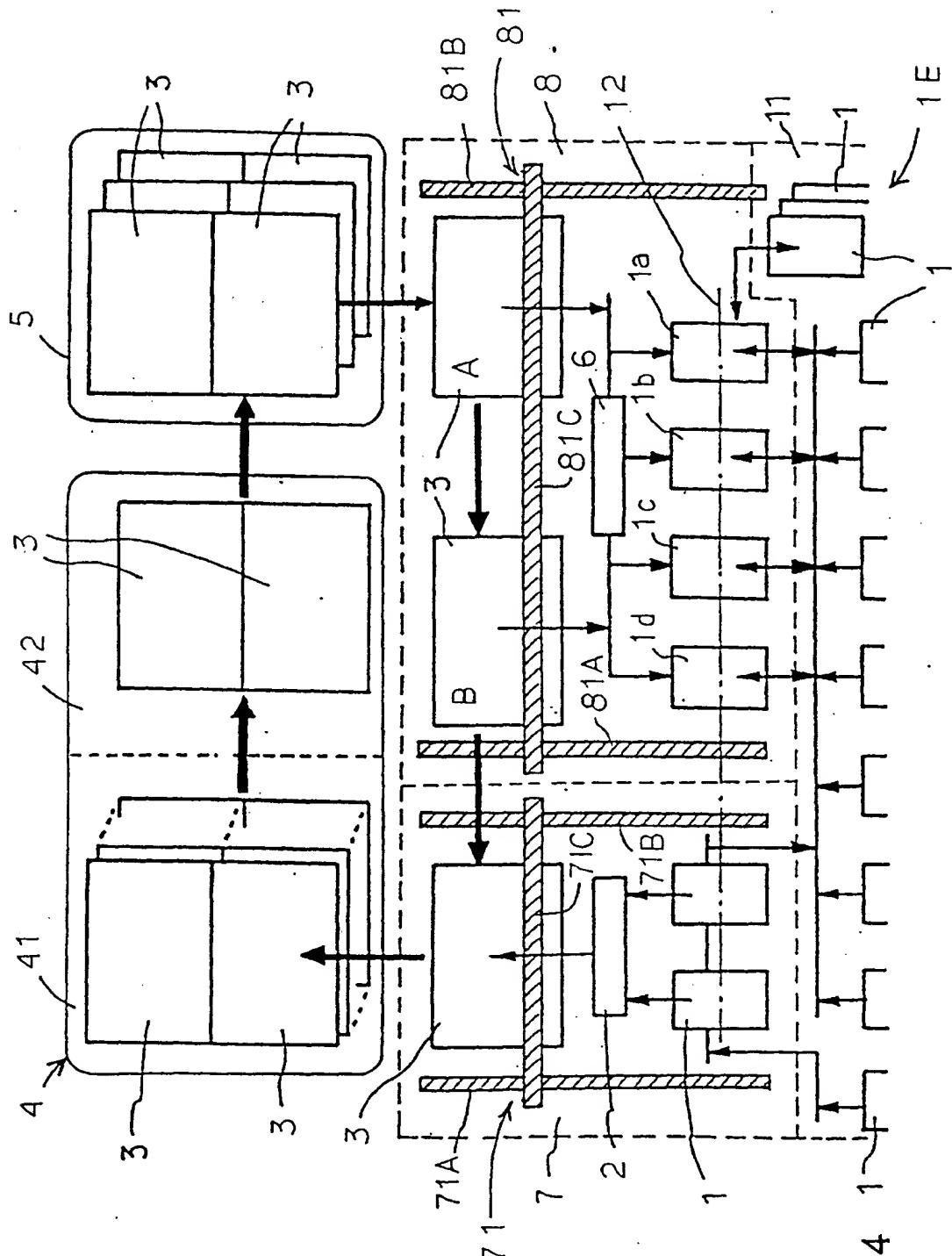


FIG. 4

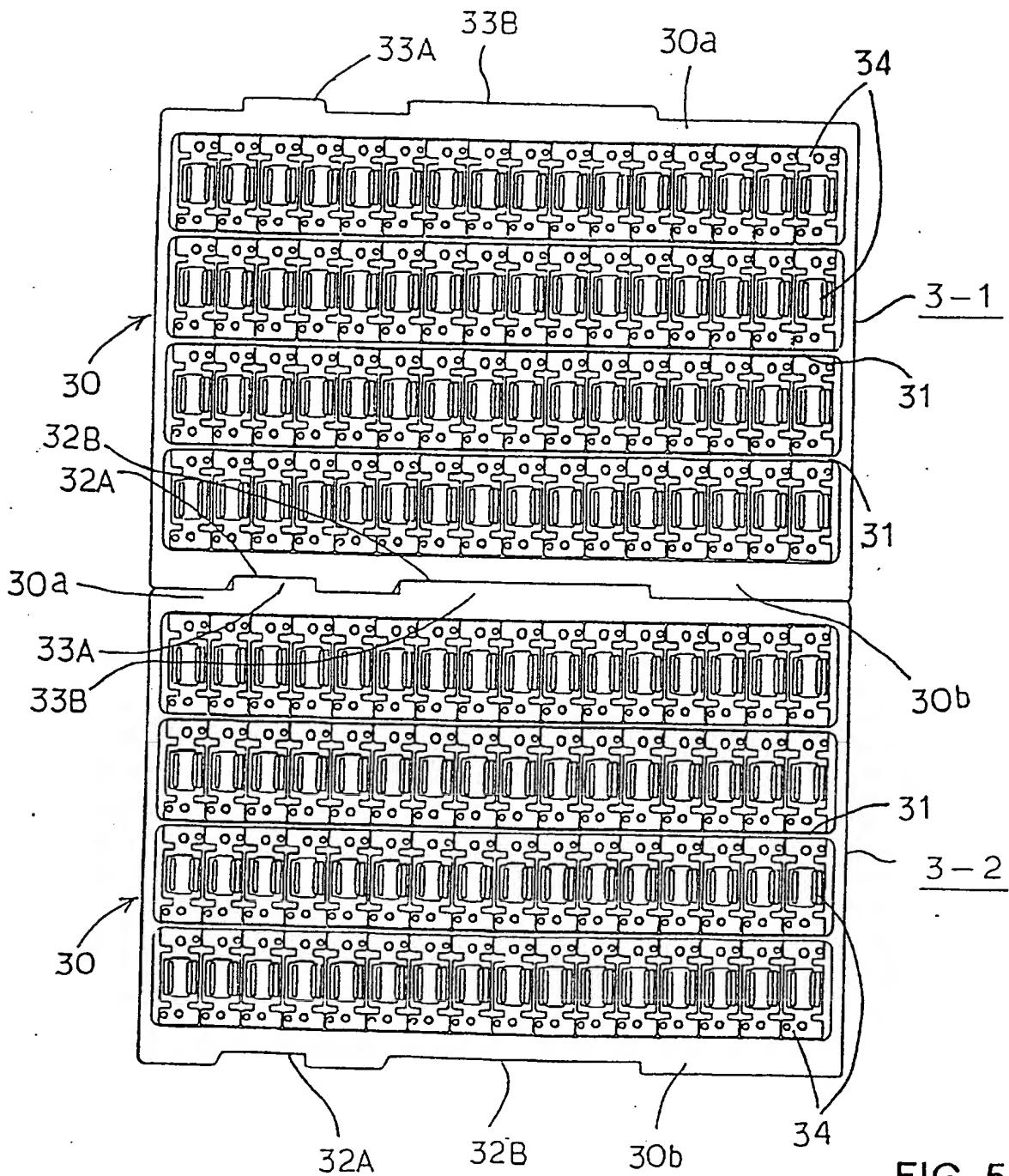


FIG. 5

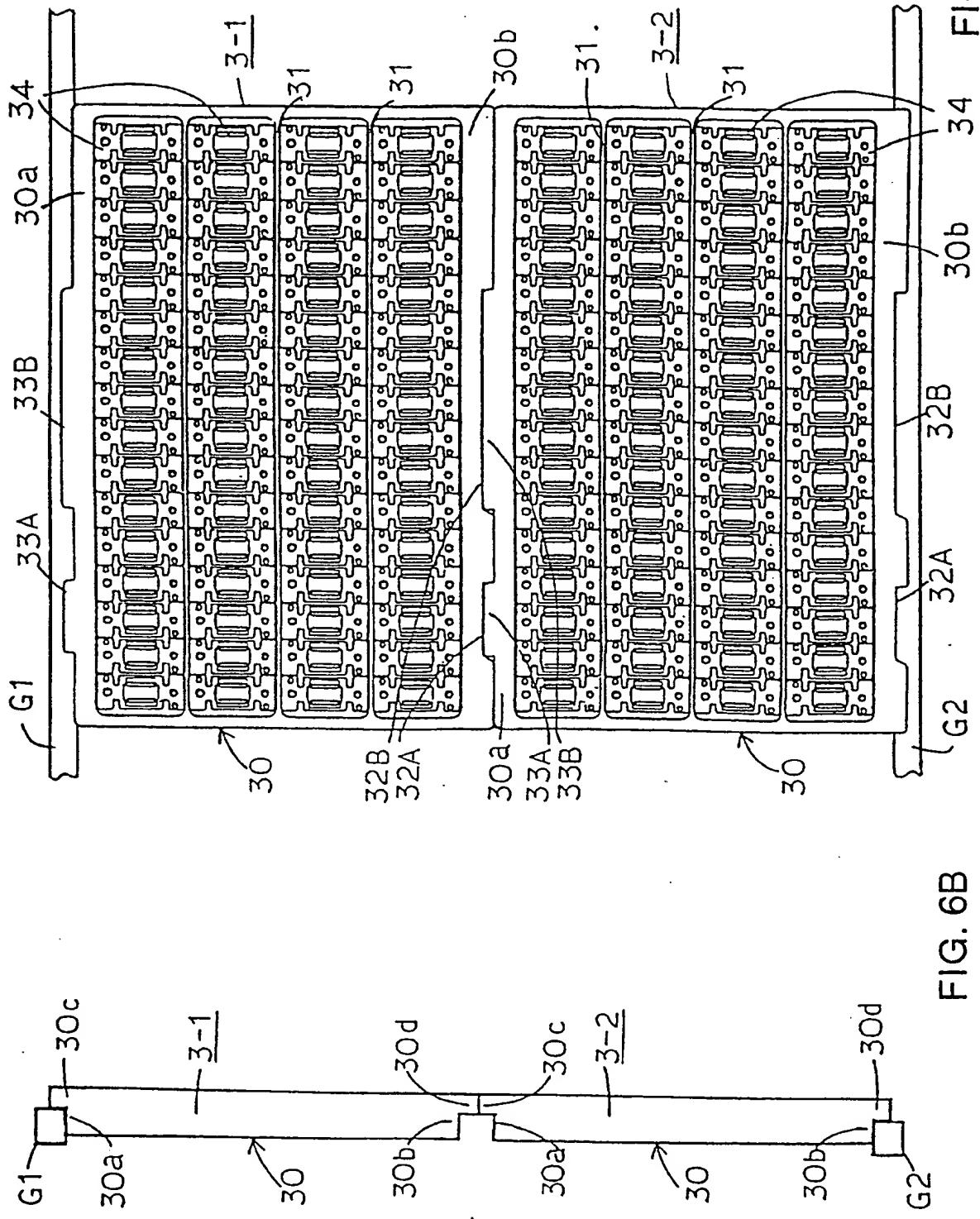


FIG. 6B

FIG. 6A

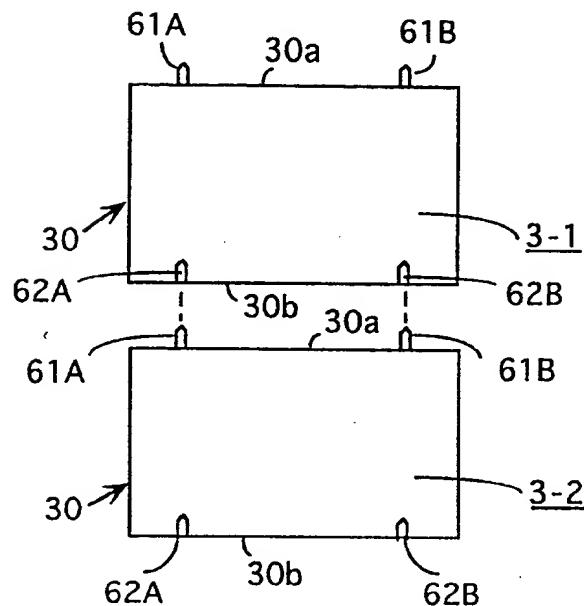


FIG. 7 A

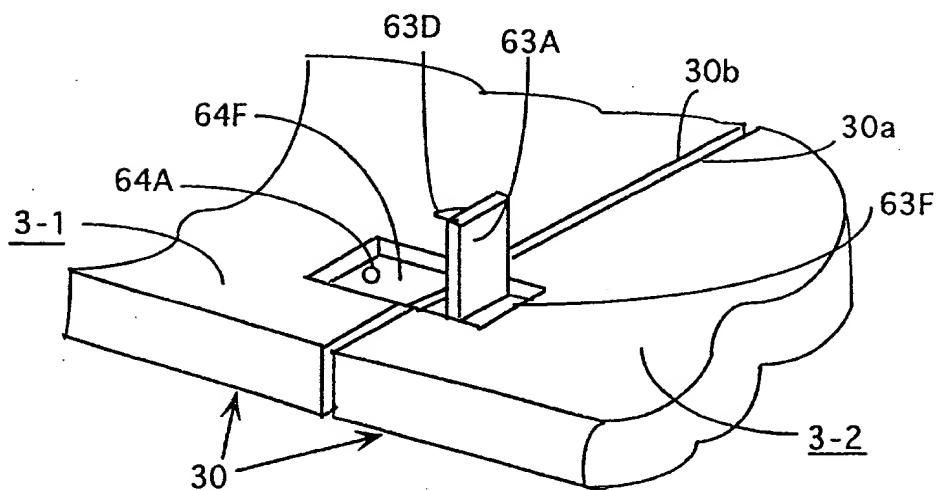


FIG. 7 B

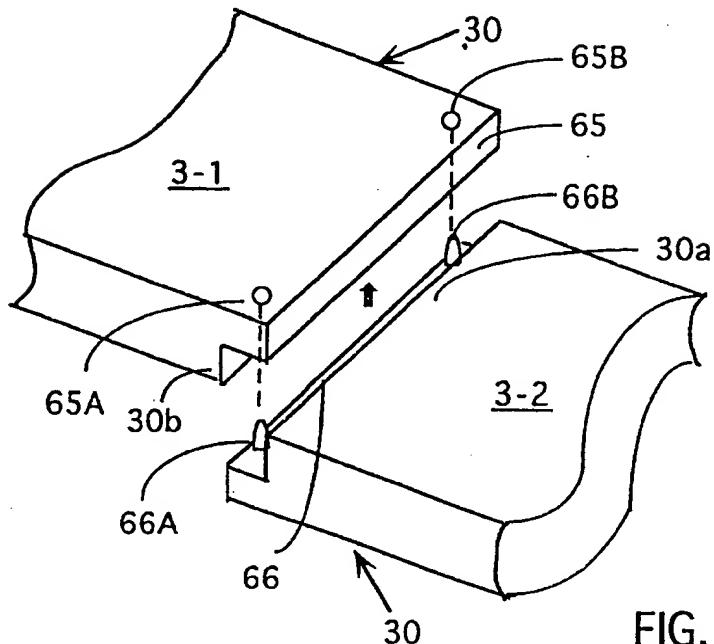


FIG. 7 C

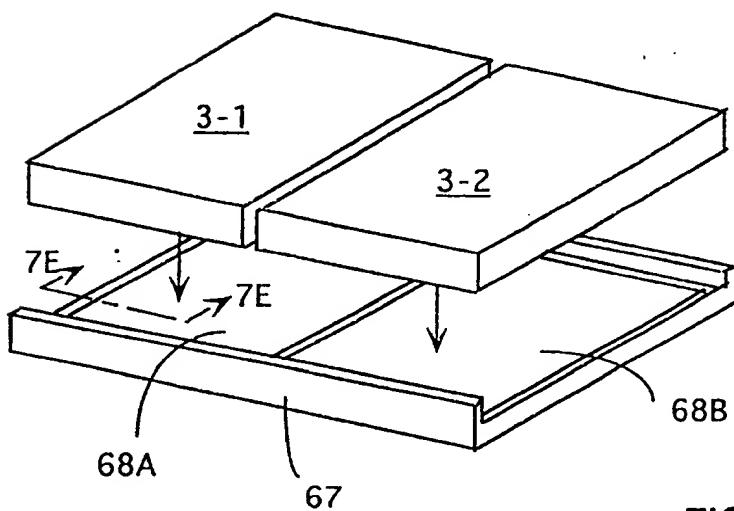


FIG. 7 D

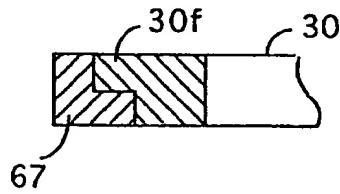
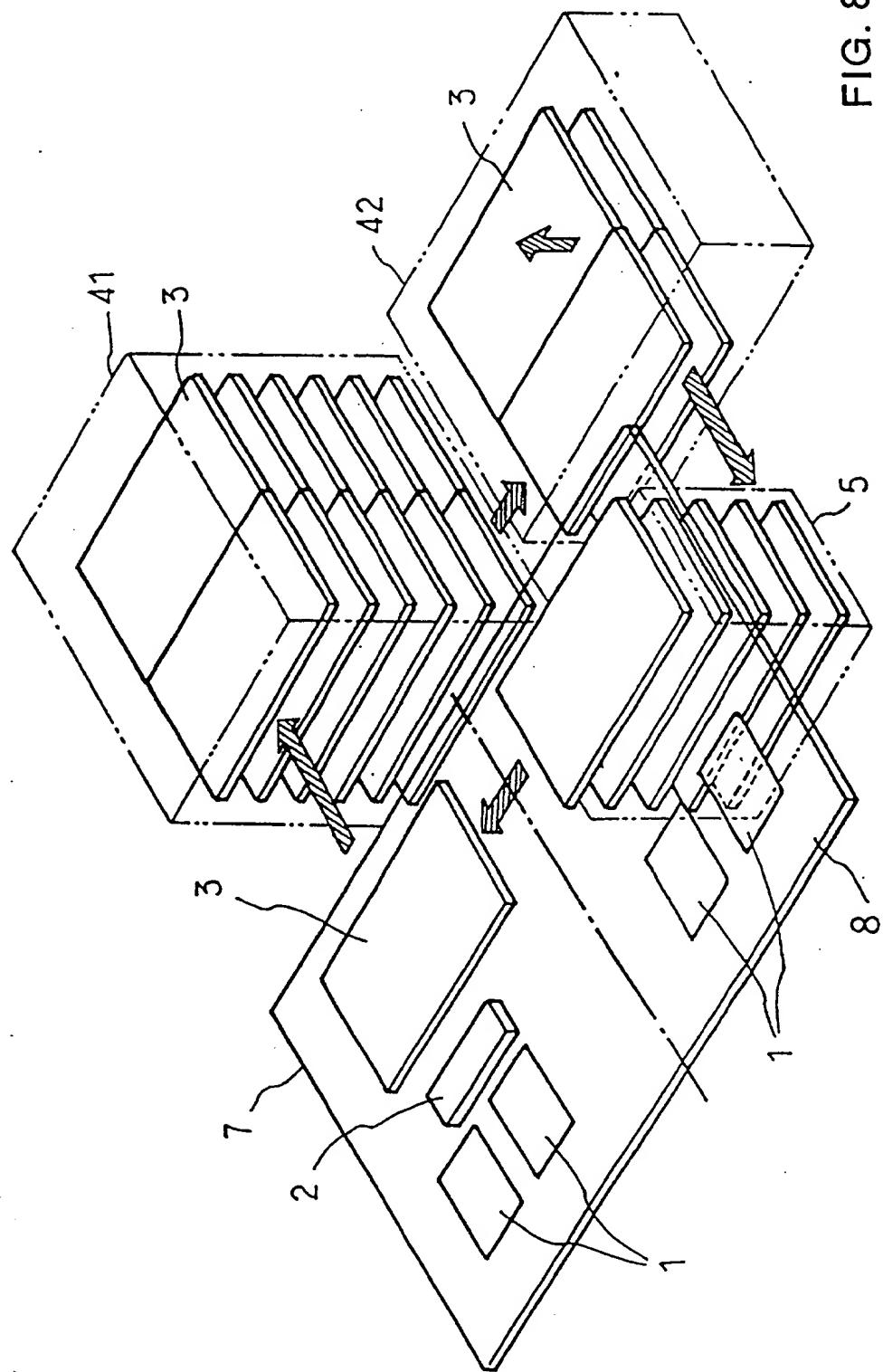


FIG. 7 E

FIG. 8



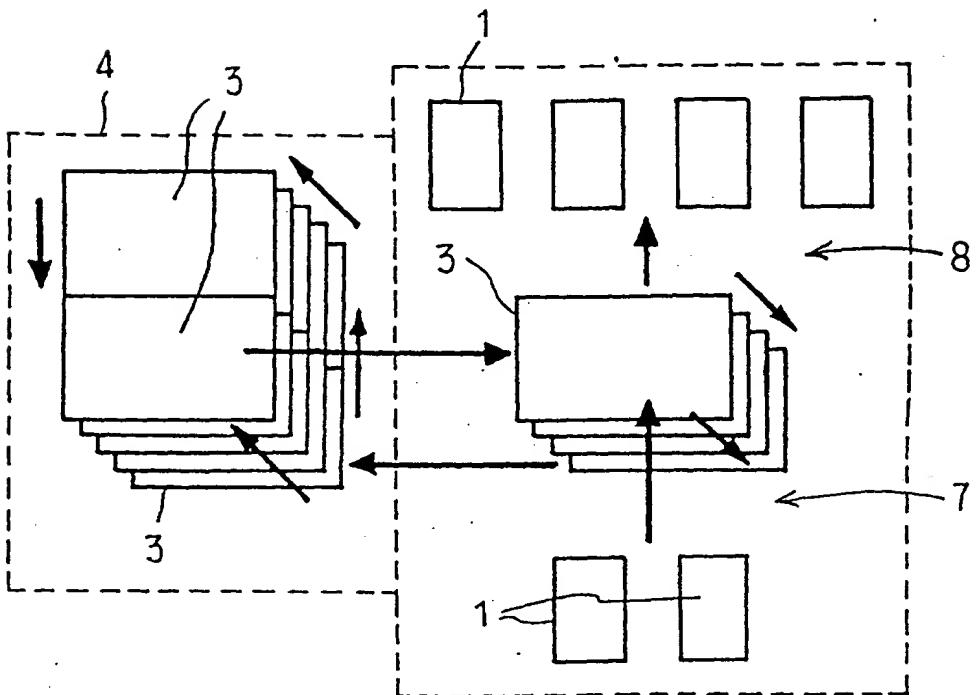


FIG. 9

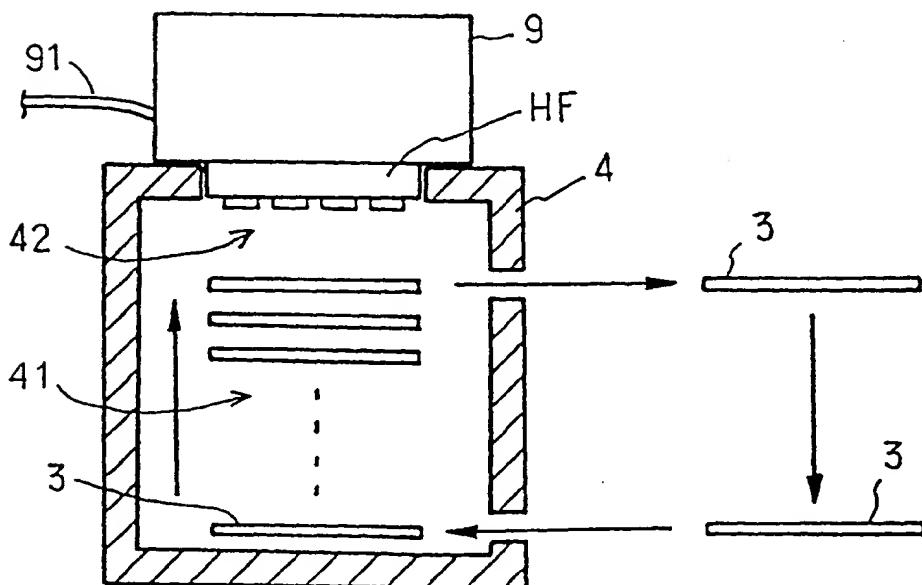


FIG. 10

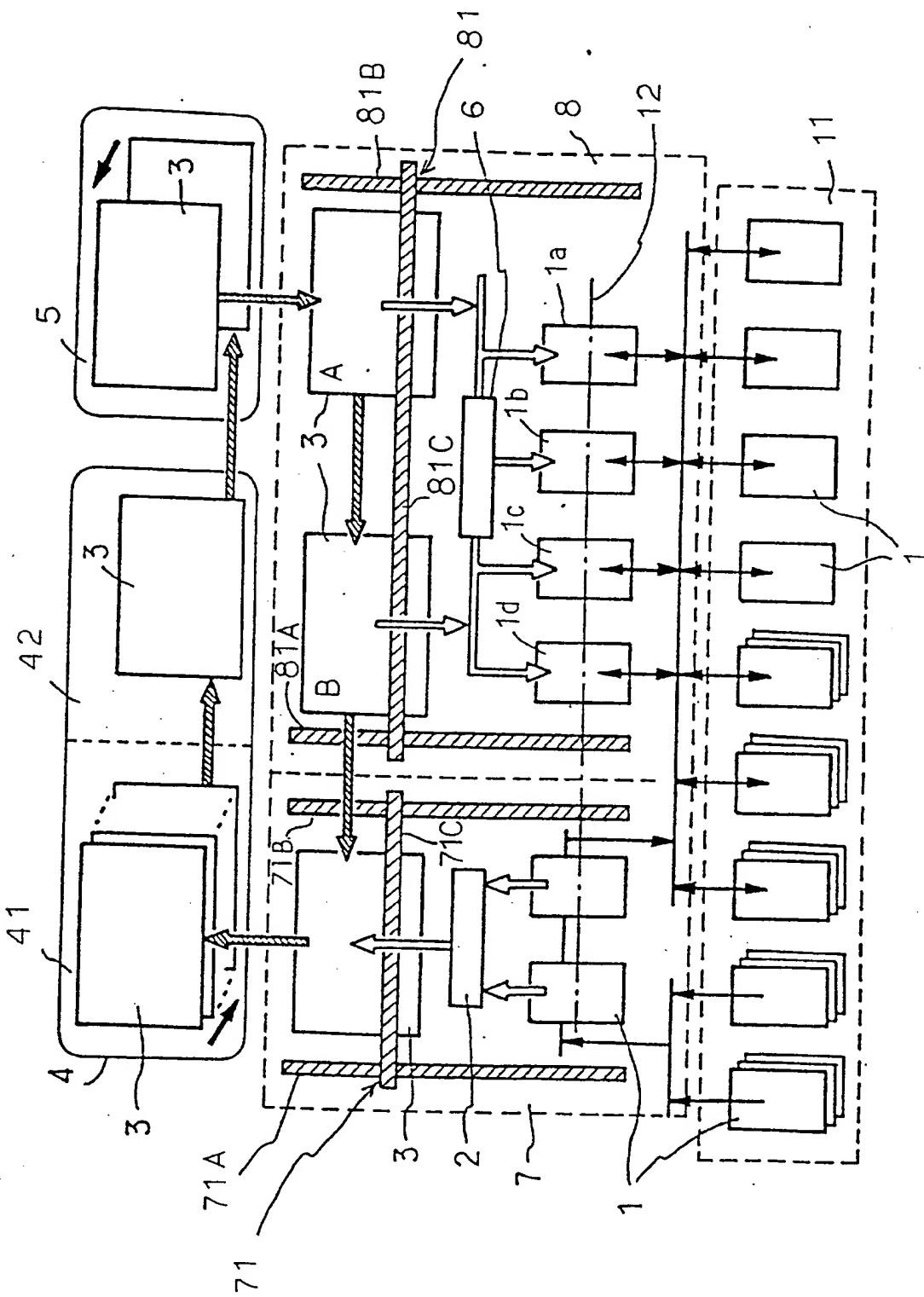


FIG. 11

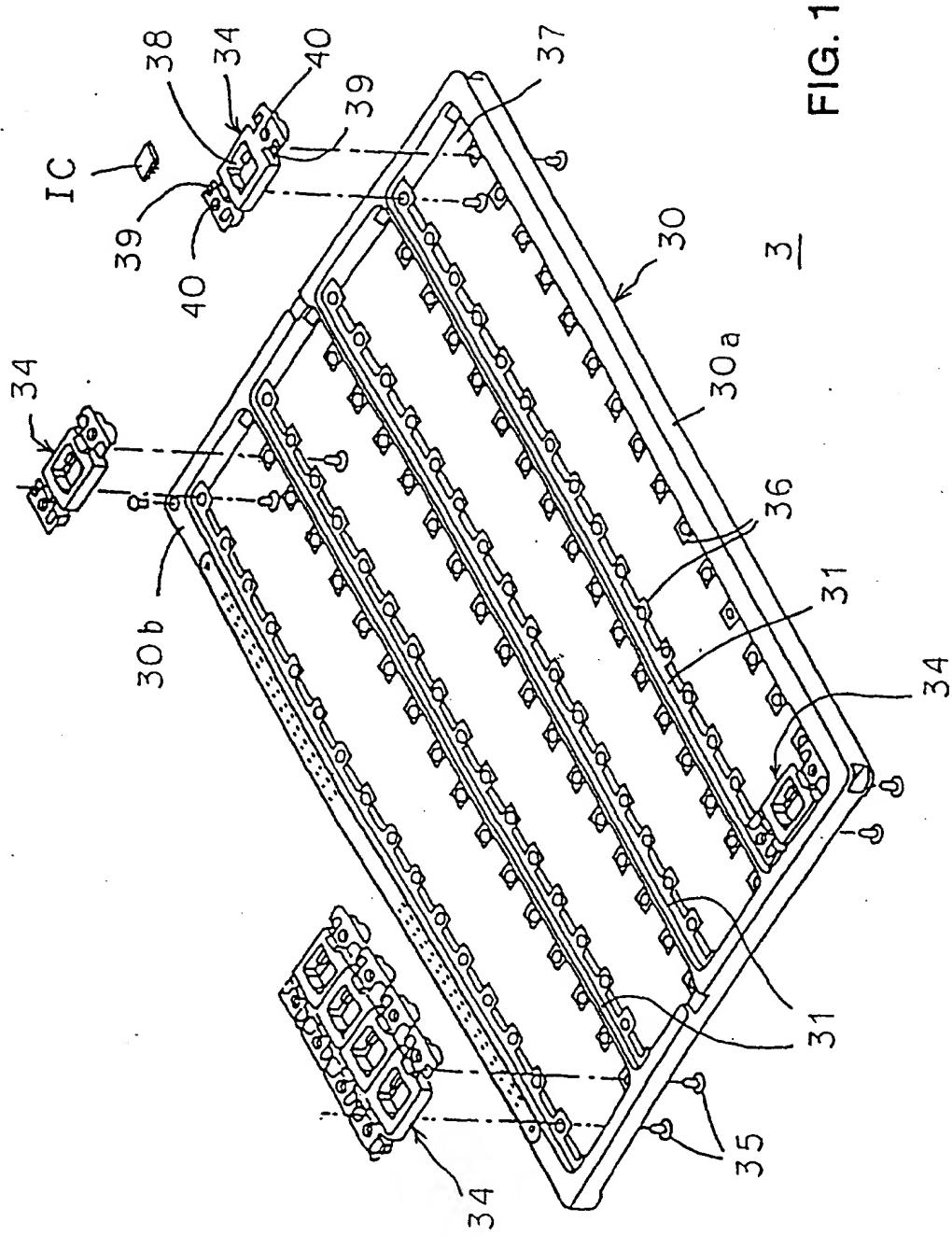


FIG. 12

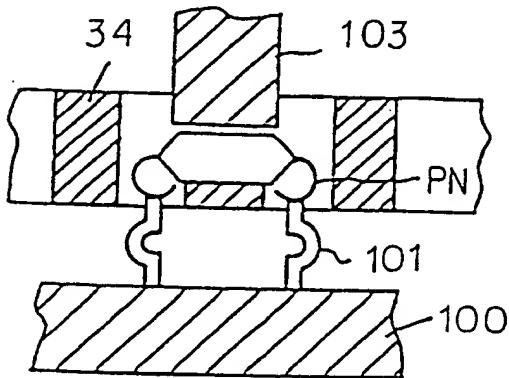


FIG. 13

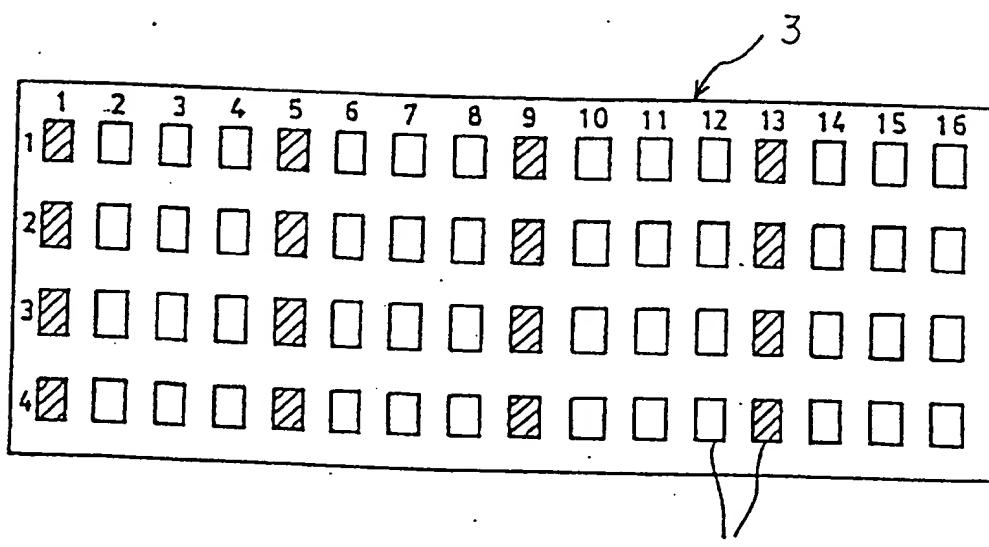


FIG. 14

Title: SEMICONDUCTOR DEVICE TESTING APPARATUS
AND A TEST TRAY FOR USE IN THE TESTING APPARATUS
Inventor: Akihiko ITO, et al.
Application No.: To Be Assigned
Docket No.: 333772000101
Sheet 14 of 14

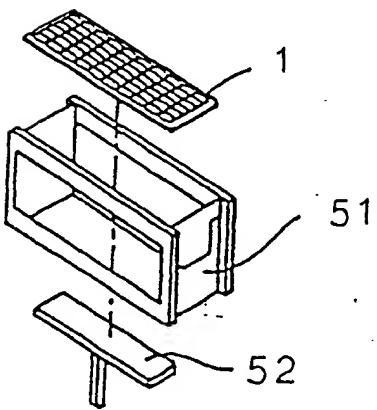


FIG. 15